





Presented to:

RAM VIII Training Summit

Effective Highly Accelerated Life Test: HALTPlus

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Highly Accelerated Life Test



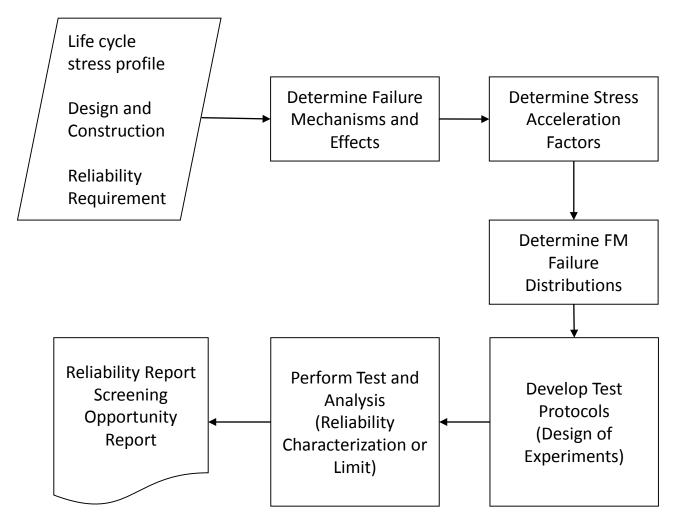
- Accelerated testing needed to assess and verify subsystem reliability
 - System level testing does not provide sufficient confidence (limited samples, test conditions and test times) for required equipment life cycle
- Typical HALT process not related to system Life
 - Stress levels usually exceed application and specified limits
 - Irrelevant failures to application may occur
 - Test profile cannot readily be correlated to system application lifetime
 - Does not provide accurate, quantifiable, reliability assessment
- Physics of Failure application to Life testing
 - Understanding failure mechanisms for a particular subsystem can allow development of accelerated tests relevant to the application

Improved HALT methodology required



HALT Plus Process







HALT Plus Application

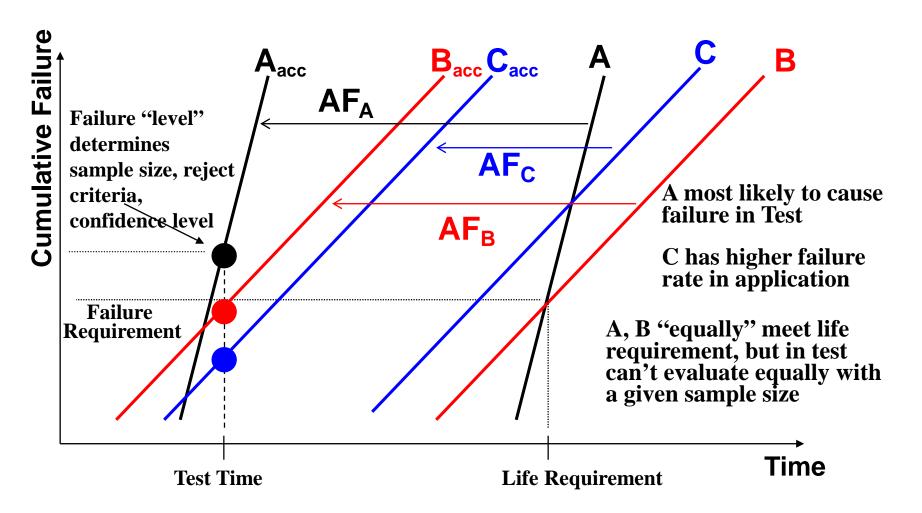


- Basic approach used on Circuit Card Assemblies for >15 years
 - Address Plastic Encapsulated Microcircuit and Solder Joint reliability
 - Can apply to other assemblies
- Identifies the need for sequential/simultaneous environments
 - Synergistic effects among environments
 - Simultaneous environments difficult to apply and model, but often preferred to address life cycle stresses
 - Temperature/humidity and temperature/vibration common simultaneous stress
 - Power cycles important effect to include
- Accelerated testing difficult to apply at high assembly levels due to competing failure mechanisms with different acceleration factors



Competing Failure Mechanisms









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